





Ultra-low power digital PDM XENSIV™ MEMS microphone

Features

- Ultra-high signal to noise ratio (SNR) of 71.5dB(A)
- Ultra-low current consumption in high performance mode (430μA) and in low power mode (160μA)
- Component level IP57 water and dust resistant
- Flat frequency response with a low frequency roll-off at 11Hz
- Package dimensions: 4mm x 3mm x 1.2mm

Potential applications

- Active Noise Cancellation (ANC) headphones and earbuds
- · High quality audio capturing
 - Laptops and tablets
 - Conference systems
 - Cameras, camcorders, and camera accessories
- Devices with Voice User Interface (VUI)
 - Smart speakers
 - Home automation
 - IOT devices
- Industrial or home monitoring with audio pattern detection

Infineon IM72D128V







Product validation

Technology qualified for industrial applications.

Ready for validation in industrial applications according to the relevant tests of IEC 60747 and 60749 or alternatively JEDEC47/20/22.

Description

The IM72D128VV01 is an ultra-high performance XENSIV™ MEMS microphone designed for applications which require a digital PDM MEMS microphone with high SNR (low self-noise), low distortion (high AOP), and very low current consumption.

Very high signal-to-noise ratio (SNR) of 71.5dB(A) enables far-field and low volume audio pick-up. The flat frequency response (11Hz low-frequency roll-off) and tight manufacturing tolerance improve performance of multi-microphone (array) applications.

The digital microphone ASIC contains an extremely low-noise preamplifier and a high-performance sigma-delta ADC. Different power modes can be selected in order to suit specific clock frequency and current consumption requirements. Each IM72D128VV01 microphone is calibrated with an advanced Infineon calibration algorithm, resulting in low sensitivity tolerances (±1dB).

Additionally, IM72D128VV01 allows for switching between different power & performance profiles without any audible artifacts.

Туре	Package	Marking
IM72D128VV01	PG-LLGA-5-3	I72D26

Datasheet





Table of contents

	Features	1
	Potential applications	1
	Product validation	1
	Description	1
	Table of contents	2
1	Block diagram	3
2	Environmental robustness	3
3	Typical performance characteristics	4
4	Acoustic characteristics	6
5	Free field frequency response	7
5.1	Free field frequency response	7
6	Electrical characteristics and parameters	8
6.1	Absolute maximum ratings	8
6.2	Electrical parameters	8
6.3	Electrical characteristics	9
6.4	Audio DC offset	10
6.5	Stereo PDM configuration	11
7	Package information	12
8	Footprint and stencil recommendation	13
9	Packing information	14
10	Reflow soldering and board assembly	15
11	Reliability specifications	16
	Revision history	18
	Disclaimer	19

1 Block diagram



1 Block diagram

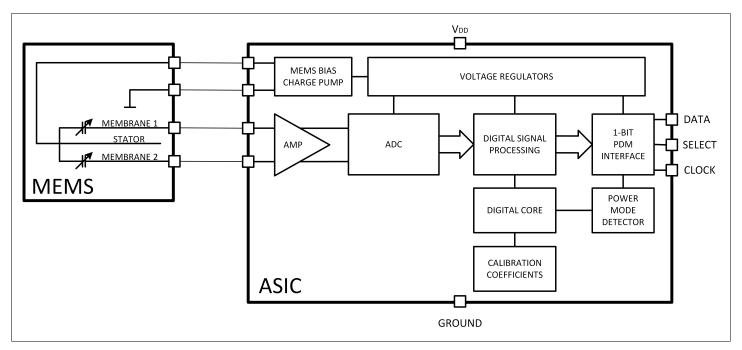


Figure 1 Block diagram

2 Environmental robustness

Infineon's latest Sealed Dual Membrane MEMS technology delivers high ingress protection (IP57) at a microphone level. The sealed MEMS design prevents water or dust from entering between membrane and backplate, preventing mechanical blockage or electric leakage issues commonly observed in MEMS microphones. Microphones built with the Sealed Dual Membrane technology can be used to create IP68 devices, requiring only minimal mesh protection.

Table 1 Environmental robustness

Test Standard	Test Condition
IP5x dust resistance ¹⁾	Arizona dust A4 coarse, vertical orientation, sound hole upwards, 10 cycles (15 minutes sedimentation, 6 sec blowing)
IPx7 water immersion ²⁾	Temporary immersion of 1 meters for 30 minutes. Microphone tested 2 hours after removal

The number "5" stands for the dust ingress rating or the capacity to withstand the effects of fine, abrasive dust particles.

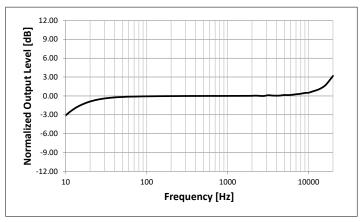
The "7" specifies the higher water immersion rating.





3 Typical performance characteristics

Test conditions: V_{DD} =1.8V, f_{CLK} =3.072MHz, T_A =25°C, unless otherwise specified.



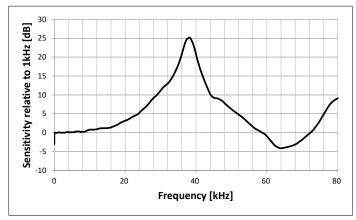


Figure 2 Typical amplitude response

90 75 60 88 45 30 15 -30 10 100 100 1000 Frequency [Hz]

Figure 3 Typical ultrasonic response

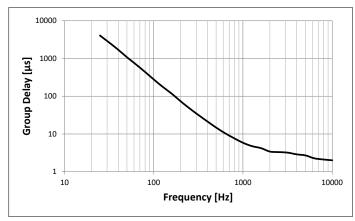


Figure 4 Typical phase response

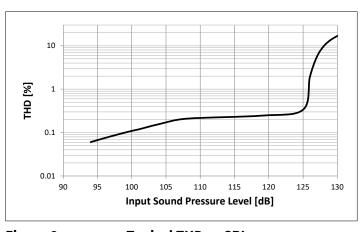


Figure 5 Typical group delay

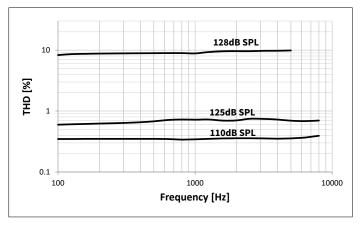


Figure 6 Typical THD vs SPL

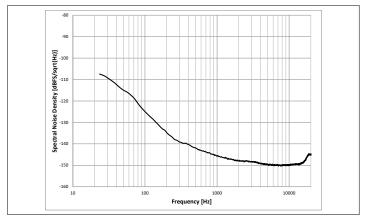
Figure 7 Typical THD vs frequency

4

Datasheet



3 Typical performance characteristics



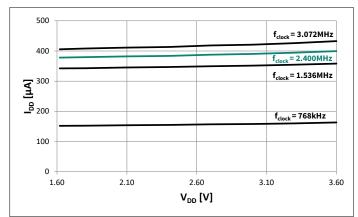


Figure 8 Typical noise floor (unweighted)

Figure 9 Typical I_{DD} vs V_{DD}

5

Datasheet

4 Acoustic characteristics



4 Acoustic characteristics

Test conditions (unless otherwise specified in the table): V_{DD} = 1.8V, f_{CLK} = 3.072MHz, OSR=64, T_A = 25°C, 55% R.H., audio bandwidth 20Hz to 20kHz, select pin grounded, no load on DATA, T_{edge} = 9ns

Table 2Acoustic specifications

Parameter		Symbol		Values		Unit	Note or Test Condition
			Min.	Тур.	Max.		
Sensitivity		S	-37	-36	-35	dBFS	1kHz, 94dBSPL, all operating modes
Low Frequency Roll-off		LFRO		11		Hz	-3dB relative to 1kHz
Resonant Frequency Peak				37.5		kHz	
Signal to Noise Ratio	F _{clock} = 768kHz	SNR		67			20Hz to 8kHz bandwidth, OSR: 48, A-Weighted
	F _{clock} = 1.536MHz			70		dB(A)	20Hz to 20kHz bandwidth, A-
	F _{clock} = 2.4MHz			70.5			Weighted
	$F_{clock} = 3.072MHz$			71.5			
Total Harmonic	94dBSPL	THD		0.1			Measuring 2nd to 5th
Distortion	125dBSPL			1.0		%	harmonics; 1kHz. S = typ, all operating modes
	128dBSPL			10.0			operating modes
Acoustic Overload Point	10% THD	AOP		128		dBSPL	Measuring 2nd to 5th harmonics; 1kHz. S = typ, all operating modes
Group Delay	250Hz			60			
	600Hz			10			
	1kHz			6		μs	
	4kHz			3.5			
Phase	75Hz			11			
Response	1kHz			-0.3		0	
	4kHz			-4			
Directivity			On	nnidirectio	onal		
Polarity			Positive pressure increases density of 1's, negative pressure decreases density of 1's in data output				

5 Free field frequency response



5 Free field frequency response

5.1 Free field frequency response

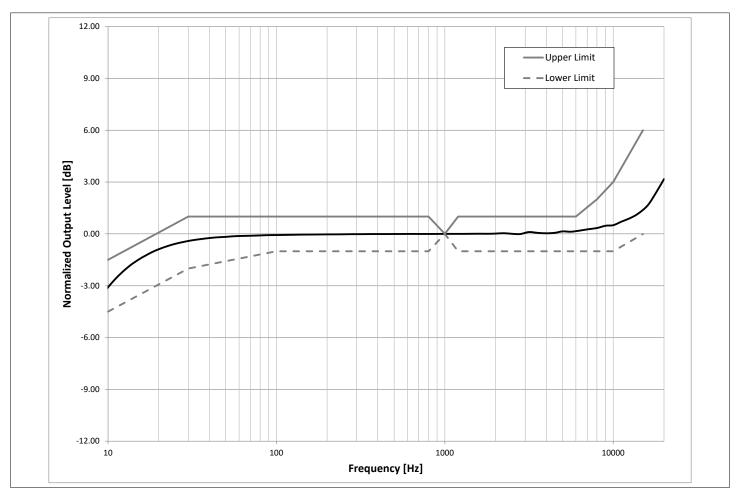


Figure 10 Free field frequency response

Table 3 Free field frequency response, normalized to 1kHz sensitivity value

Frequency [Hz]	Upper limit [dB]	Lower limit [dB]
10	-1.5	-4.5
30	1	-2
100	1	-1
800	1	-1
1000	0	0
1200	1	-1
6000	1	-1
8000	2	-1
10000	3	-1
15000	6	0

6 Electrical characteristics and parameters



6 Electrical characteristics and parameters

6.1 Absolute maximum ratings

Stresses exceeding the listed maximum ratings may affect device reliability or cause permanent device damage. Functional device operation at these conditions is not guaranteed.

Table 4 Absolute maximum ratings

Parameter	Symbol	Values		Unit	Note / Test Condition
		Min.	Max.		
Voltage on any Pin	V _{max}		3.6	V	
Storage Temperature	T _S	-40	125	°C	
Ambient Temperature	T _A	-40	85	°C	

6.2 Electrical parameters

Table 5 Electrical parameters and digital interface input

Parameter		Symbol	ol Values		Unit	Note / Test Condition	
			Min.	Тур.	Max.		
Supply Volta	ge	V_{DD}	1.62	1.8	3.6	V	3)
Clock	Standby Mode	f _{clock}			330	kHz	4)
Frequency Range	Low Power Mode		380	480	640	kHz	5)
Nange			730	768	1020	kHz	
Normal Mode High	Normal Mode		1.17	1.536	1.70	MHz	
			1.9	2.4	2.6	MHz	
	Performance Mode		2.9	3.072	3.4	MHz	
V _{DD} Ramp-up	Time				50	ms	Time until V _{DD} ≥ V _{DD_min}
Input Logic L	ow Level	V _{IL}			0.3xV _{DD}	V	
Input Logic H	ligh Level	V _{IH}	0.7xV _{DD}			V	
Clock Rise/Fa	all Time				13	ns	10% to 90%
Clock Duty C	ycle		45		55	%	
Output Load DATA	Capacitance on	C _{load}			100	pF	

A $1\mu F$ bypass capacitor should be placed close to the microphone V_{DD} pad to ensure best SNR performance.

⁴ Data pad is high impedance in standby mode.

Parameter not subject to productive test. Verified by laboratory characterization/design.

6 Electrical characteristics and parameters



6.3 Electrical characteristics

Test conditions (unless otherwise specified in the table): $V_{DD} = 1.8V$, $f_{CLK} = 3.072$ MHz, $T_A = 25$ °C, 55% R.H.

Table 6 General electrical characteristics

clock Off Mode tandby Mode clock = 768kHz clock = 1.536MHz clock = 2.4MHz clock = 3.072MHz rent fection 0.5dB sensitivity ccuracy	I _{clock_off} I _{standby} I _{DD} PSR _{1k_NM}	Min.	90 160 350 390 430 -80	Max. 1 120 230 525 20	μA mA dBFS	CLOCK pulled low No load on DATA <5pF load on DATA Grounded DATA pin 100mV _{pp} sine wave on V _{DD} swept from 200Hz to 20kHz.
tandby Mode clock = 768kHz clock = 1.536MHz clock = 2.4MHz clock = 3.072MHz rent ection 0.5dB sensitivity ccuracy	I _{standby} I _{DD}	1	160 350 390 430	120 230 525	mA dBFS	No load on DATA <5pF load on DATA Grounded DATA pin 100mV _{pp} sine wave on V _{DD} swept from 200Hz to 20kHz.
clock = 768kHz clock = 1.536MHz clock = 2.4MHz clock = 3.072MHz rent fection 0.5dB sensitivity ccuracy	I _{standby} I _{DD}	1	160 350 390 430	230 525	dBFS	<pre><5pF load on DATA Grounded DATA pin 100mV_{pp} sine wave on V_{DD} swept from 200Hz t 20kHz.</pre>
clock = 1.536MHz clock = 2.4MHz clock = 3.072MHz rent fection 0.5dB sensitivity ccuracy	I _{DD}	1	350 390 430 -80	525	dBFS	Grounded DATA pin 100mV _{pp} sine wave on V _{DD} swept from 200Hz t 20kHz.
clock = 2.4MHz clock = 3.072MHz ent ection 0.5dB sensitivity ccuracy		1	390 430 -80		dBFS	100mV _{pp} sine wave on V _{DD} swept from 200Hz t 20kHz.
ection 0.5dB sensitivity ccuracy		1	430 -80		dBFS	100mV _{pp} sine wave on V _{DD} swept from 200Hz t 20kHz.
ection 0.5dB sensitivity ccuracy		1	-80		dBFS	100mV _{pp} sine wave on V _{DD} swept from 200Hz t 20kHz.
0.5dB sensitivity		1		20	dBFS	100mV _{pp} sine wave on V _{DD} swept from 200Hz t 20kHz.
0.5dB sensitivity ccuracy						20kHz.
ccuracy	PSR _{217_NM}		-86		dBES(A)	100
ccuracy					abi 3(A)	100mV _{pp} , 217Hz square wave on V _{DD} . A-weighte
				20	ms	Time to start up in any operating modes after V _{DD_min} and CLOCK hav been applied. ⁶⁾
0.2dB sensitivity ccuracy				50		
0.5dB sensitivity ccuracy				20	ms	Time to switch between operating modes. V _{DD}
0.2dB sensitivity ccuracy				50		remains on during the mode switch. ⁶⁾
/ Level	V _{OL}			0.2xV _{DD}	V	
n Level	V _{OH}	0.8xV _{DD}				
Delay Time for DATA Driven		40		80	ns	Delay time from CLOCK edge (0.5xV _{DD}) to DATA driven.
Delay Time for DATA High-Z ⁷⁾		5		30	ns	Delay time from CLOCK edge (0.5xV _{DD}) to DATA high impedance state
Delay Time for DATA Valid ⁸⁾				100	ns	Delay time from CLOCK edge (0.5xV _{DD}) to DATA valid (<0.3xV _{DD} or >0.7xV _{DD})
o control of the cont	curacy .2dB sensitivity curacy Level Level TA Driven	curacy .2dB sensitivity curacy Level V _{OL} Level V _{OH} TA Driven t _{DD} TA High-Z ⁷⁾ t _{HZ} TA Valid ⁸⁾ t _{DV}	curacy .2dB sensitivity curacy _evel	curacy .2dB sensitivity curacy Level V _{OL} Level V _{OH} 0.8xV _{DD} TA Driven t _{DD} 40 TA High-Z ⁷⁾ t _{HZ} 5 TA Valid ⁸⁾ t _{DV}	curacy 50 .2dB sensitivity 50 curacy 0.2xV _{DD} Level V _{OL} 0.8xV _{DD} TA Driven t _{DD} 40 80 TA High-Z ⁷⁾ t _{HZ} 5 30 TA Valid ⁸⁾ t _{DV} 100 ur Idle tone is output over PDM within 3ms of any or position. 100	curacy .2dB sensitivity curacy 50 .2evel V_{OL} $0.2xV_{DD}$ V .2evel V_{OH} $0.8xV_{DD}$.7A Driven t_{DD} 40 80 ns .7A High- Z^{7} t_{HZ} 5 30 ns .7A Valid ⁸⁾ t_{DV} 100 t_{DV} .2. Idle tone is output over PDM within 3ms of applying V_{DV} a valid microphone signal is available. Idle tone consi

Verified at typical PDM clock frequencies for each power mode.

 $^{^{7}}$ t_{hold} is dependent on C_{load}

⁸ Load on data: C_{load} =100pF, R_{load} =100k Ω





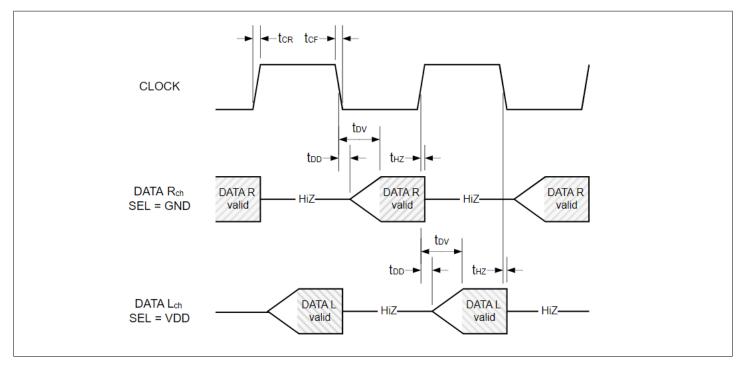


Figure 11 Timing diagram

6.4 Audio DC offset

The DC output level encoded in the DC bit stream is determined by the L/R state on startup. In each case the DC output level is stable over time and does not vary with input signal level.

Table 7 DC output level using L/R pin

LR state	DC output level (typical)	Unit
LR = GND	-80	dBFS
LR = VDD	-40	dBFS

10

6 Electrical characteristics and parameters



6.5 Stereo PDM configuration

The IM72D128VV01 is designed to function in circuits with one or two microphones on the PDM bus. When two microphones are connected, data is transmitted alternately according to the L/R pin status of each microphone. When two microphones are connected to a shared PDM bus, the power modes of both microphones will be the same as both are controlled by the same PDM clock. The performance is unchanged relative to a single microphone per bus configuration.

Table 8 PDM channel configuration using L/R pin.

Channel	Data driven	Data high-Z	L/R connection
DATA1	Falling clock edge	Rising clock edge	GND
DATA2	Rising clock edge	Falling clock edge	V_{DD}

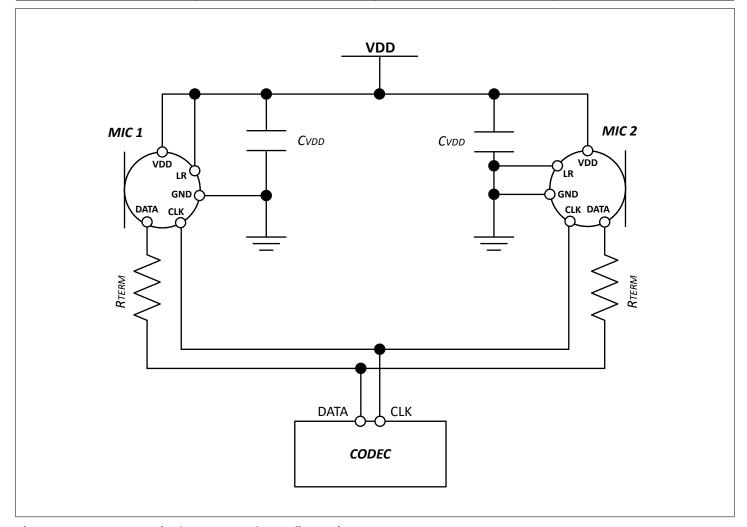


Figure 12 Typical stereo mode configuration

Note:

For best performance it is strongly recommended to place a 100nF (C_{VDD_typ}) capacitor between V_{DD} and ground for each microphone. The capacitor should be placed as close to V_{DD} as possible. A termination resistor (R_{TERM}) of about 100 Ω may be added to reduce the ringing and overshoot on the output signal.

7 Package information



7 Package information

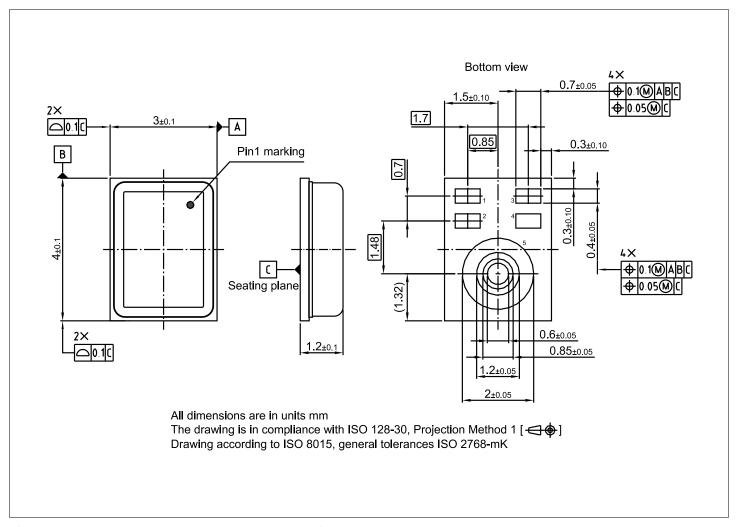


Figure 13 IM72D128VV01 package drawing

Table 9 IM72D128VV01 pin configuration

Pin Number	Name	Description	
1	DATA	PDM data output	
2	V_{DD}	Power supply	
3	CLOCK	PDM clock input	
4	LR	PDM left/right select	
5	GND	Ground	

8 Footprint and stencil recommendation



8 Footprint and stencil recommendation

The acoustic port hole diameter in the PCB should be larger than the acoustic port hole diameter of the MEMS microphone to ensure optimal performance. A PCB sound port size of radius 0.4mm (diameter 0.8 mm) is recommended.

The board pad and stencil aperture recommendations shown in Figure 14 are based on Non-Solder Mask Defined (NSMD) pads. The specific design rules of the board manufacturer should be considered for individual design optimizations or adaptations.

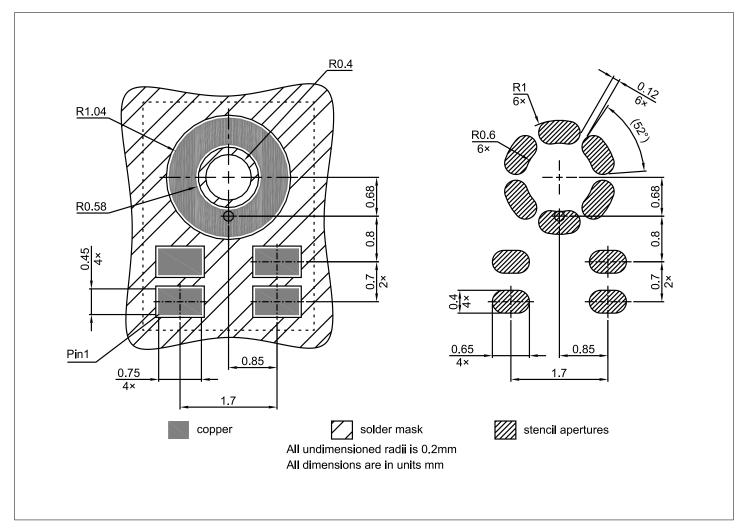


Figure 14 Footprint and stencil recommendation

9 Packing information



9 Packing information

For shipping and assembly the Infineon microphones are packed in product specific tape-and-reel carriers. A detailed drawing of the carrier can be seen in

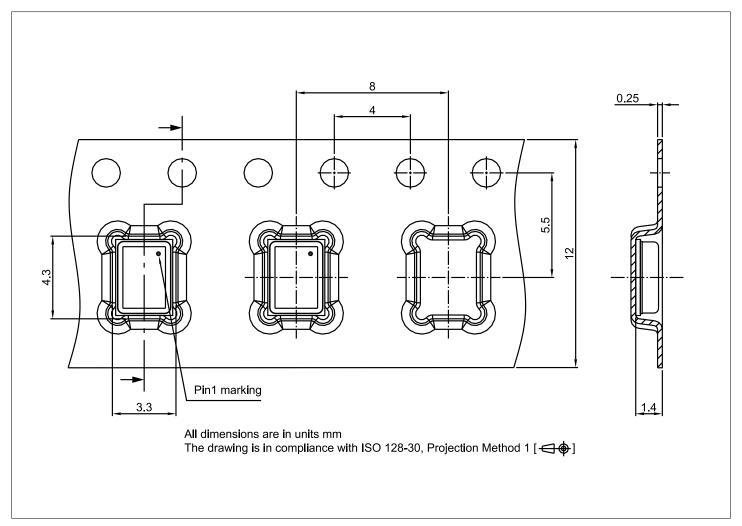


Figure 15 IM72D128VV01 tape and reel packing information

Table 10 IM72D128VV01 packaging information

Product	Type code	Reel diameter	Quantity per reel
IM72D128VV01	172D26	13"	5000

10 Reflow soldering and board assembly



10 Reflow soldering and board assembly

Infineon MEMS microphones are qualified in accordance with the IPC/JEDEC J-STD-020D-01. The moisture sensitivity level of MEMS microphones is rated as MSL1. For PCB assembly of the MEMS microphone the widely used reflow soldering using a forced convection oven is recommended.

The soldering profile should be in accordance with the recommendations of the solder paste manufacturer to reach an optimal solder joint quality. The reflow profile shown in Figure 16 is recommended for board manufacturing with Infineon MEMS microphones.

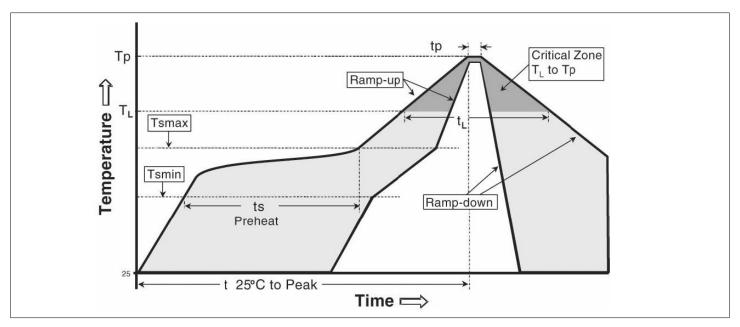


Figure 16 Recommended reflow profile

Table 11 Reflow profile limits

Profile feature	Pb-Free assembly	Sn-Pb Eutectic assembly	
Temperature Min (T _{smin})	150 °C	100 °C	
Temperature Max (T _{smax})	200 °C	150 °C	
Time (T _{smin} to T _{smax}) (t _s)	60-120 seconds	60-120 seconds	
Ramp-up rate (T _L to T _P)	3 °C/second max.	3 °C/second max.	
Liquidous temperature (T _L)	217 °C	183 °C	
Time (t _L) maintained above T _L	60-150 seconds	60-150 seconds	
Peak Temperature (T _p)	260°C +0°C/-5°C	235°C +0°C/-5°C	
Time within 5°C of actual peak temperature (tp) ⁹⁾	20-40 seconds	10-30 seconds	
Ramp-down rate	e 6 °C/second max. 6 °C/second m		
Time 25°C to peak temperature	8 minutes max.	6 minutes max.	

Note: For further information please consult the 'General recommendation for assembly of Infineon packages' document which is available on the Infineon Technologies web page

Tolerance for peak profile temperature (T_p) is defined as a supplier minimum and a user maximum

Datasheet

11 Reliability specifications



The MEMS microphones can be handled using industry standard pick and place equipment. Care should be taken to avoid damage to the microphone structure as follows:

- Do not pick the microphone with vacuum tools which make contact with the microphone acoustic port hole.
- The microphone acoustic port hole should not be exposed to vacuum, this can destroy or damage the MEMS.
- Do not blow air into the microphone acoustic port hole. If an air blow cleaning process is used, the port hole must be sealed to prevent particle contamination.
- It is recommended to perform the PCB assembly in a clean room environment in order to avoid microphone contamination.
- Air blow and ultrasonic cleaning procedures shall not be applied to MEMS Microphones. A no-clean paste is
 recommended for the assembly to avoid subsequent cleaning steps. The microphone MEMS can be severely
 damaged by cleaning substances.
- To prevent the blocking or partial blocking of the sound port during PCB assembly, it is recommended to cover the sound port with protective tape during PCB sawing or system assembly.
- Do not use excessive force to place the microphone on the PCB. The use of industry standard pick and place tools is recommended in order to limit the mechanical force exerted on the package.

11 Reliability specifications

The microphone sensitivity after stress must deviate by no more than 3dB from the initial value.

Table 12 Reliability specification

Test	Abbreviation	Test Condition	Standard
Low Temperature Operating Life	LTOL	T _a =-40°C, VDD=3.6V, 1000 hours	JESD22-A108
Low Temperature Storage Life	LTSL	T _a =-40°C, 1000 hours	JESD22-A119
High Temperature Operation Life	HTOL	T _a =+125°C, VDD=3.6V, 1000 hours	JESD22-A108
High Temperature Storage Life	HTSL	T _a =+125°C, 1000 hours	JESD22-A103
Temperature Cycling	PC + TC	Pre conditioning MSL-1	JESD22-A113
		1000 cycles, -40°C to +125°C, 30 minutes per cycle	JESD22-A104
Temperature Humidity Bias	PC + THB	Pre conditioning MSL-1	JESD22-A113
		T _a =+85°C, R.H = 85%, VDD=3.6V, 1000 hours	JESD22-A101
Vibration Test	VVF	20Hz to 2000Hz with a peak acceleration of 20g in X, Y, and Z for 4 minutes each, total 4 -cycles	IEC 60068-2-6
Mechanical Shock	MS	10000g/0.1msec direction ±x,y,z, 5 shocks in each direction, 5 shocks in total	IEC 60068-2-27
Reflow Solder ¹⁰⁾	RS	3 reflow cycles, peak temperature = +260°C	IPC-JEDEC J-STD-020D-01

(table continues...)

The microphone sensitivity must deviate by no more than 1dB from the initial value after 3 reflow cycles.

Datasheet

11 Reliability specifications



Table 12 (continued) Reliability specification

Test	Abbreviation	Test Condition	Standard
Electrostatic Discharge -System Level Test	ESD - SLT	3 discharges of ±8kV direct contact to lid while V _{dd} is supplied according to the operational modes; (V _{dd} ground is separated from earth ground)	IEC-61000-4-2
Electrostatic Discharge - Human Body Model	ESD - HBM	1 pulse of ±2kV between all I/O pin combinations	JEDEC-JS001
Electrostatic Discharge - Charged Device Model	ESD - CDM	3 discharges of ±500V direct contact to I/O pins.	JEDEC JS-002

Datasheet





Revision history

Document version	Date of release	Description of changes
v1.0	2024-06-05	Initial release
v1.1	2025-02-25	Fixed typos, no change in acoustic or electrical performance

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